

Search Notes

Application/Control No.

10/650,336

Examiner

Y. Lee

Applicant(s)/Patent under
Reexamination

KAWA ET AL.

Art Unit

2621

SEARCHED

Class	Subclass	Date	Examiner
375	240.01 240.13 240.21 240.25 **	1/11/2007	YL
	240.26		
H04N	7/12		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR